

Search Notes

Application/Control No.

10/714,642

Examiner

Tan Le

Applicant(s)/Patent under
Reexamination

TAKENAKA ET AL.

Art Unit

3632

SEARCHED

Class	Subclass	Date	Examiner
248	636	1/2/06	R
	637		
	638)	/
	559)	
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180	651-657		
910	83	300,	
477	363		
	93		
475	150		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Text Search	1/2/06	R
Consulted H-phan	/	/
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner